

# *Wafer level packaging based on wafer bonding and TSVs for advanced MEMS integration*

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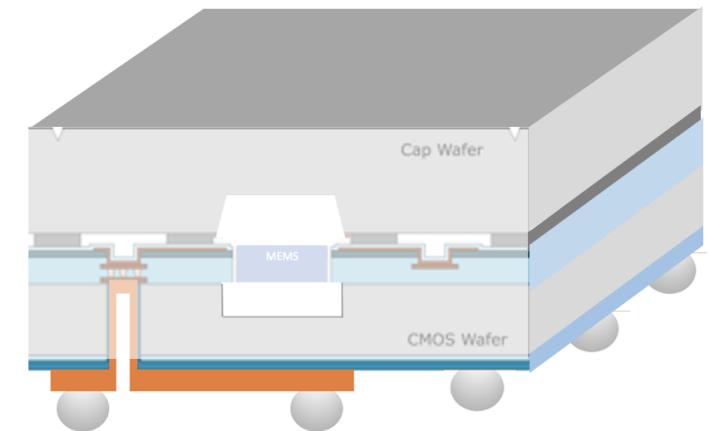
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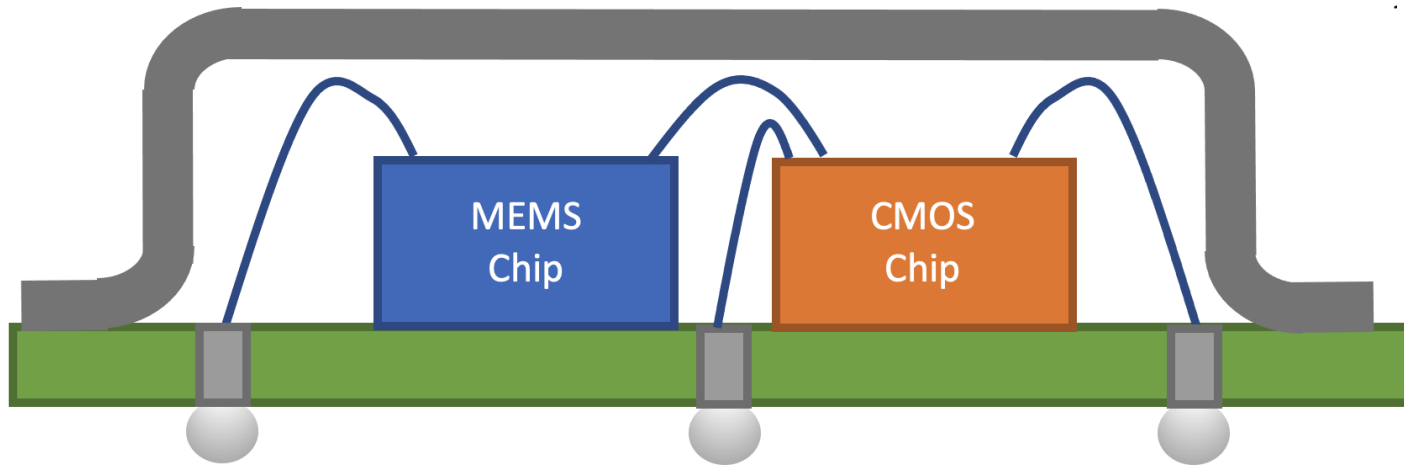


Chemnitzer Seminar / 13. Juni 2023 - 14. Juni 2023

**Electronic Packaging and Applications**



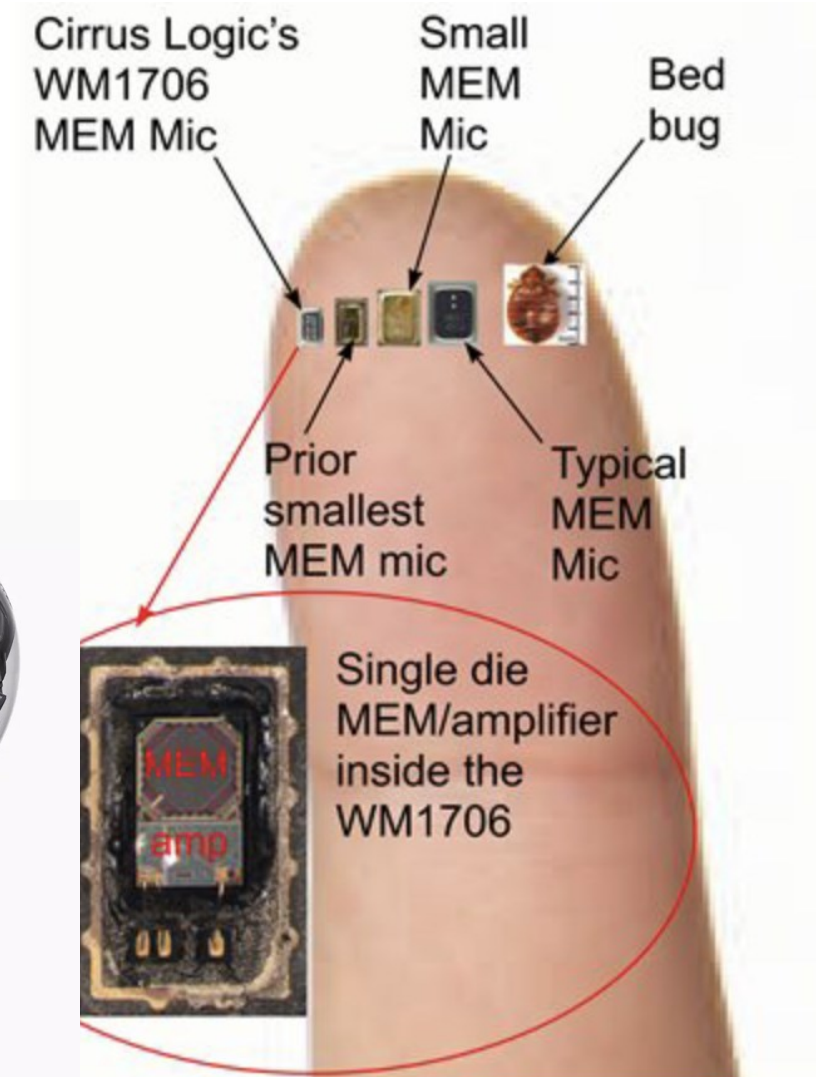
# System in Package vs. System on Chip



System in Package (SiP) – Package is the integration level widely used – standard, different solutions

- + flexible combination of MEMS and CMOS
- form factor – rather big and bulky
- distributed supply chain (foundry, assembly house)

SoC is focus of the presentation, how to realize process



## Introduction

- The principle of System on Chip and Wafer Level Packaging
- The Basic Process Integration Scheme

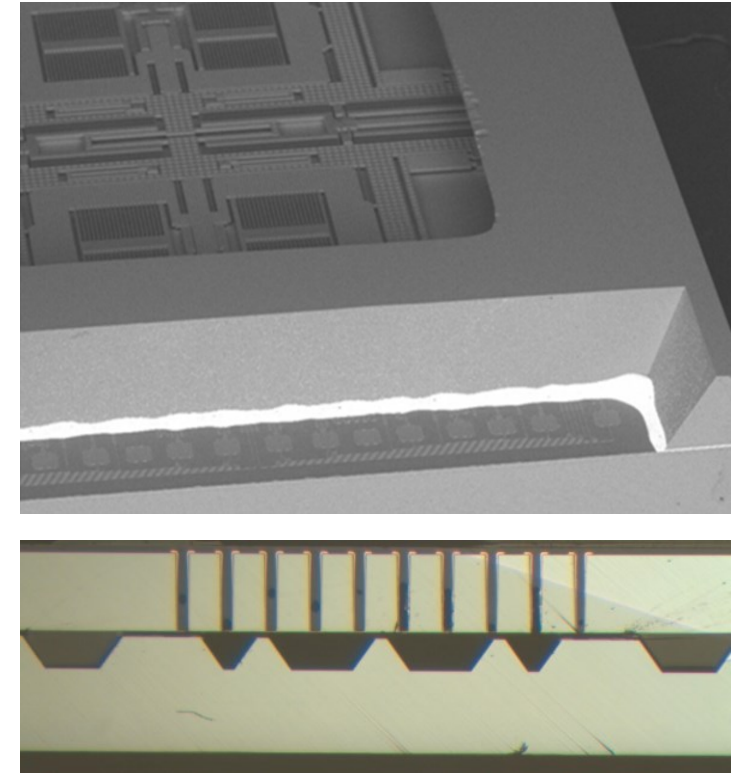
## The Basic Process Modules

- Monolithic Integration of MEMS and CMOS
- Wafer Bonding
- Through Silicon Vias
- Finishing after Wafer TSV Process

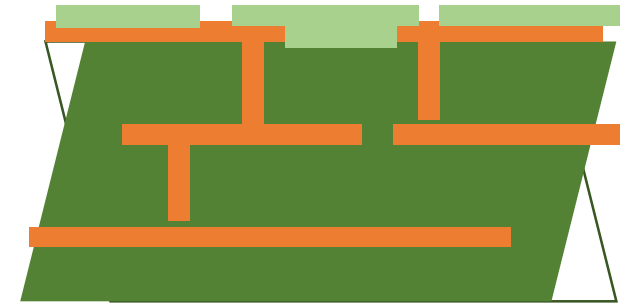
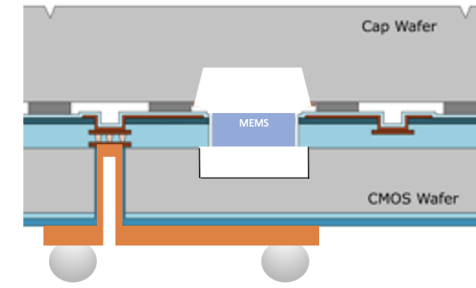
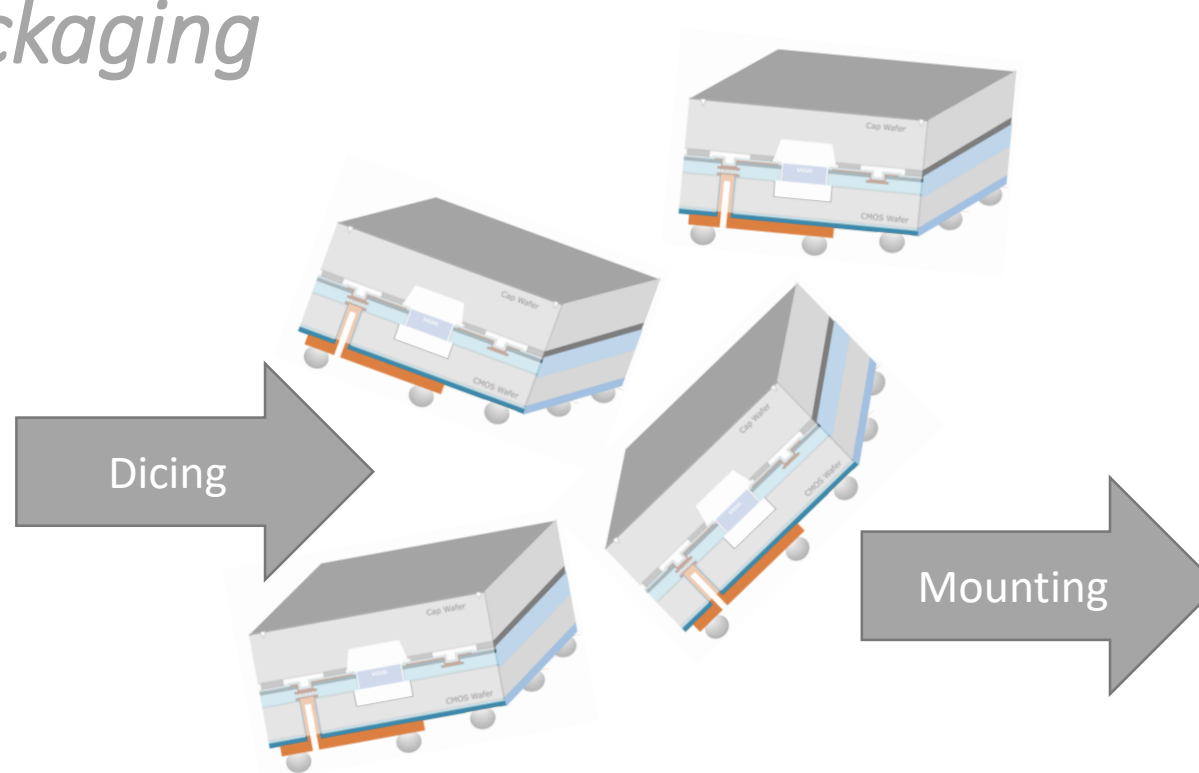
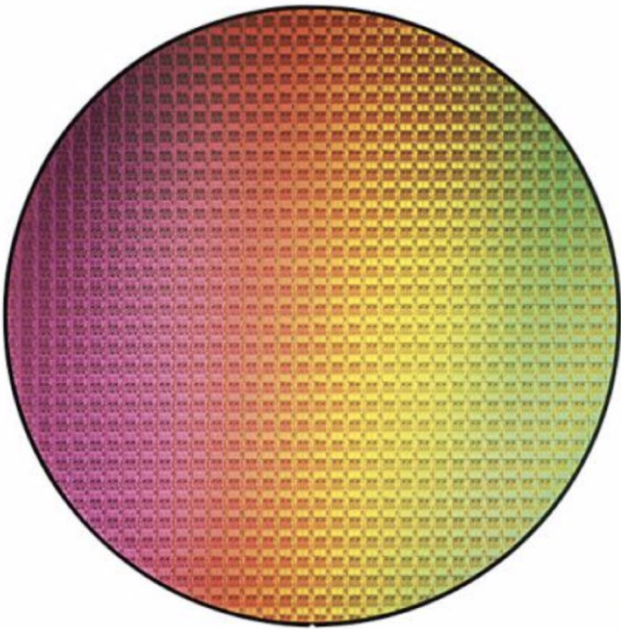
## An Example of a System on Chip – Chip Scale Package Solutions

## Application Aspects and Special Challenges

## Conclusions and Outlook



# The principle of System on Chip and Wafer Level Packaging



Do **all** the processing on wafer level

- Highest integration
- Parallel processing
- Cost efficient

Chips directly **ready for mounting on board**

- All functionalities (CMOS, MEMS)
- Solder balls or solder pads
- Passivation and solder stop
- Smallest possible form factor

**Highly integrated boards**

- BCB or Ceramics
- Small solutions
- High functionality

# The basic process integration scheme

Application Idea  
Concept

Electronic  
Functions  
CMOS

Sensor and  
other Functions  
MEMS

Fully Functional Chip

Capping, Sealing, Protecting  
WAFER BONDING

BCB and Ceramics  
Requirements

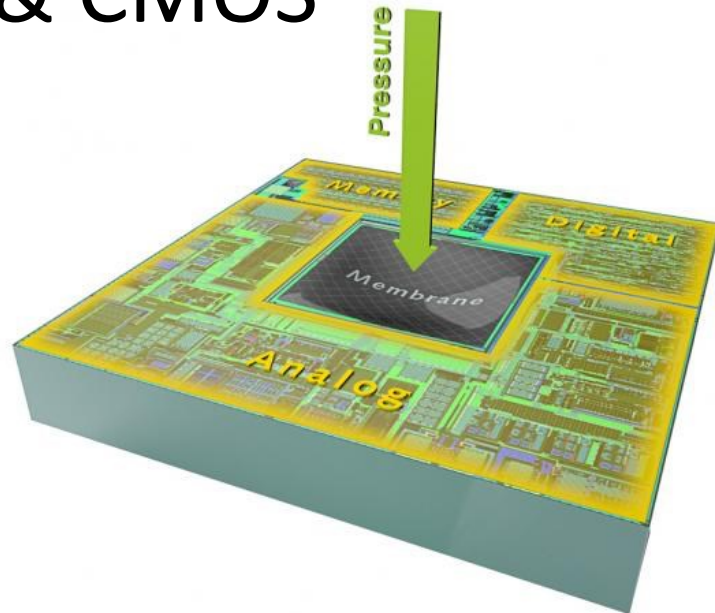
Modular  
Approach for  
Flexibility in  
Development  
and Production

Contacting  
TSV, BGA, UBM, SOL-STOP

Materials  
Processes  
Design  
Reliability

Wafer Process  
FOUNDRY / IDM

## Monolithic Integration MEMS & CMOS



## Wafer Bonding



## TSVs



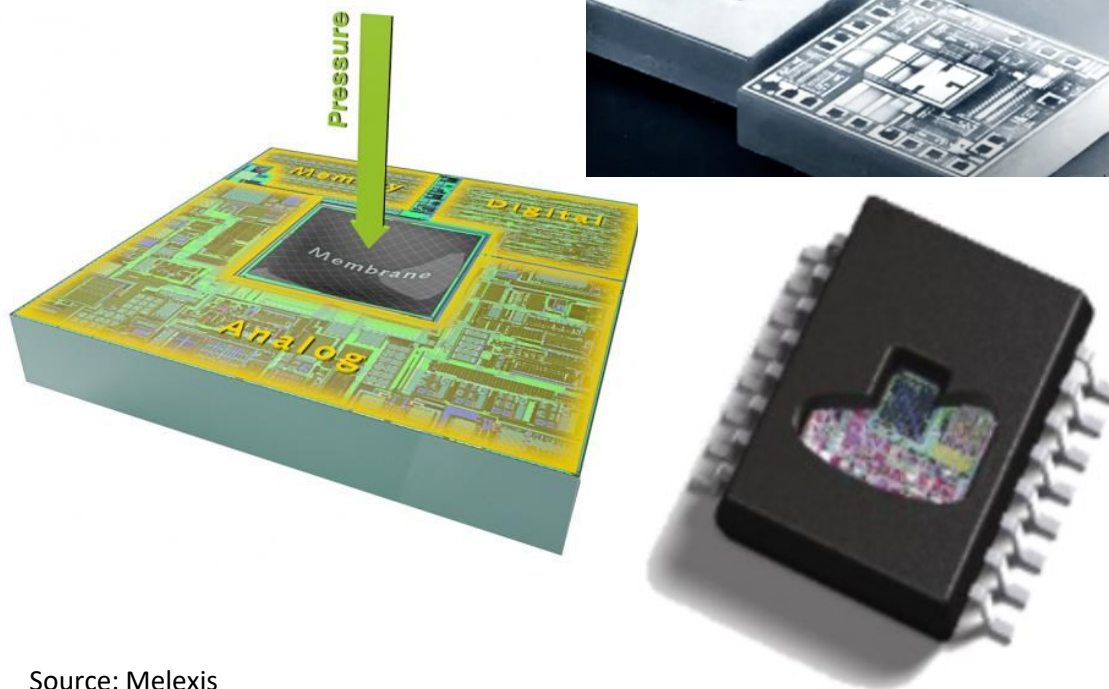
... with RDL, UBM, Solder Stop

# ... and how all can fit together

## MEMS Devices requires electronics

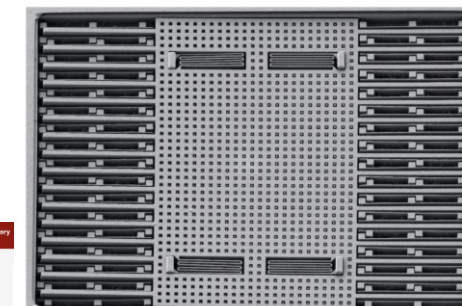
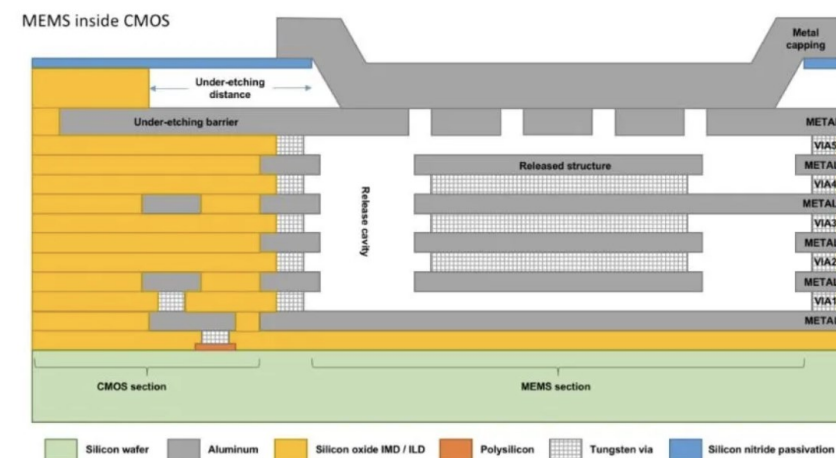
- Signal processing, sensor signal improving, driving signals,....
- Integration of MEMS and CMOS on one and the same wafer/chip is well established

### Bulk Micromachining



Source: Melexis

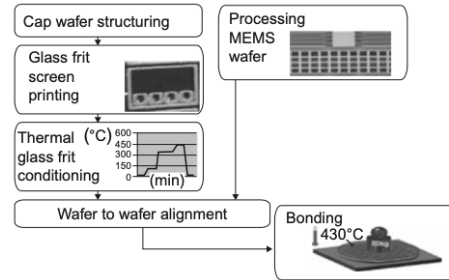
### Surface Micromachining



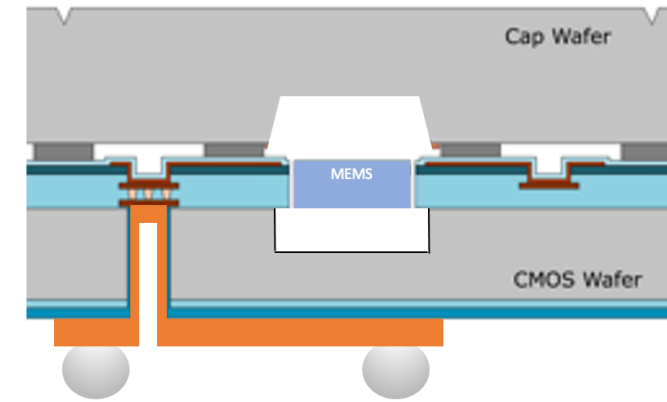
A 2D motion sensor built in 0.18-µm CMOS (Image: Nanosens)



Wafer Level Capping  
nearly no processes after wafer bonding  
Dicing



Glass Frit Bonding  
still very attractive  
process  
Costs  
Process Integration



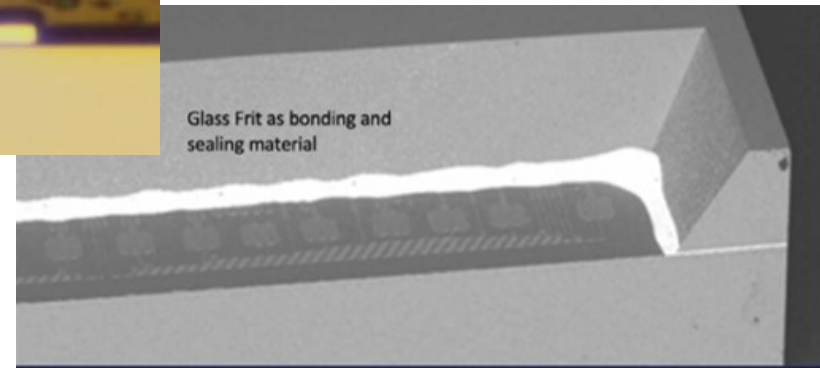
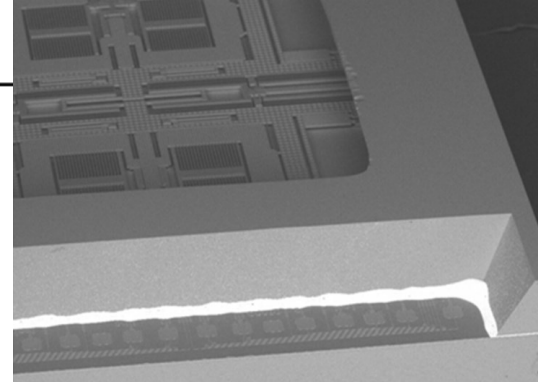
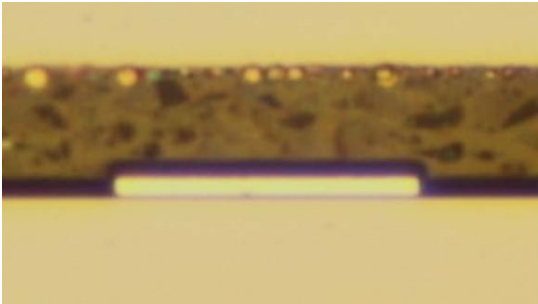
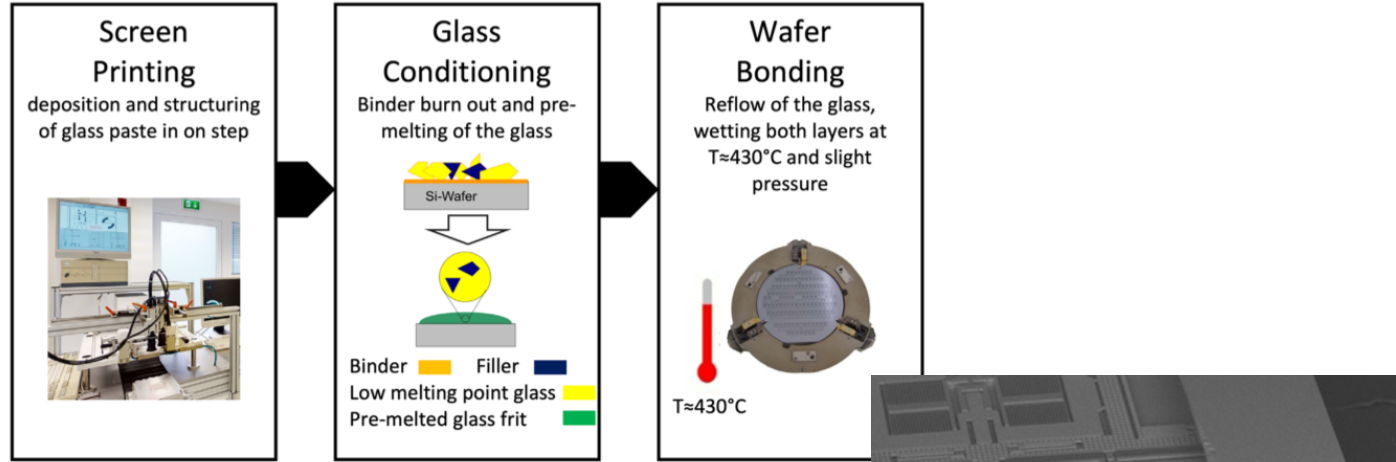
Wafer Level Packaging  
many processes after wafer bonding  
TSV  
RDL/UBM  
Bumping



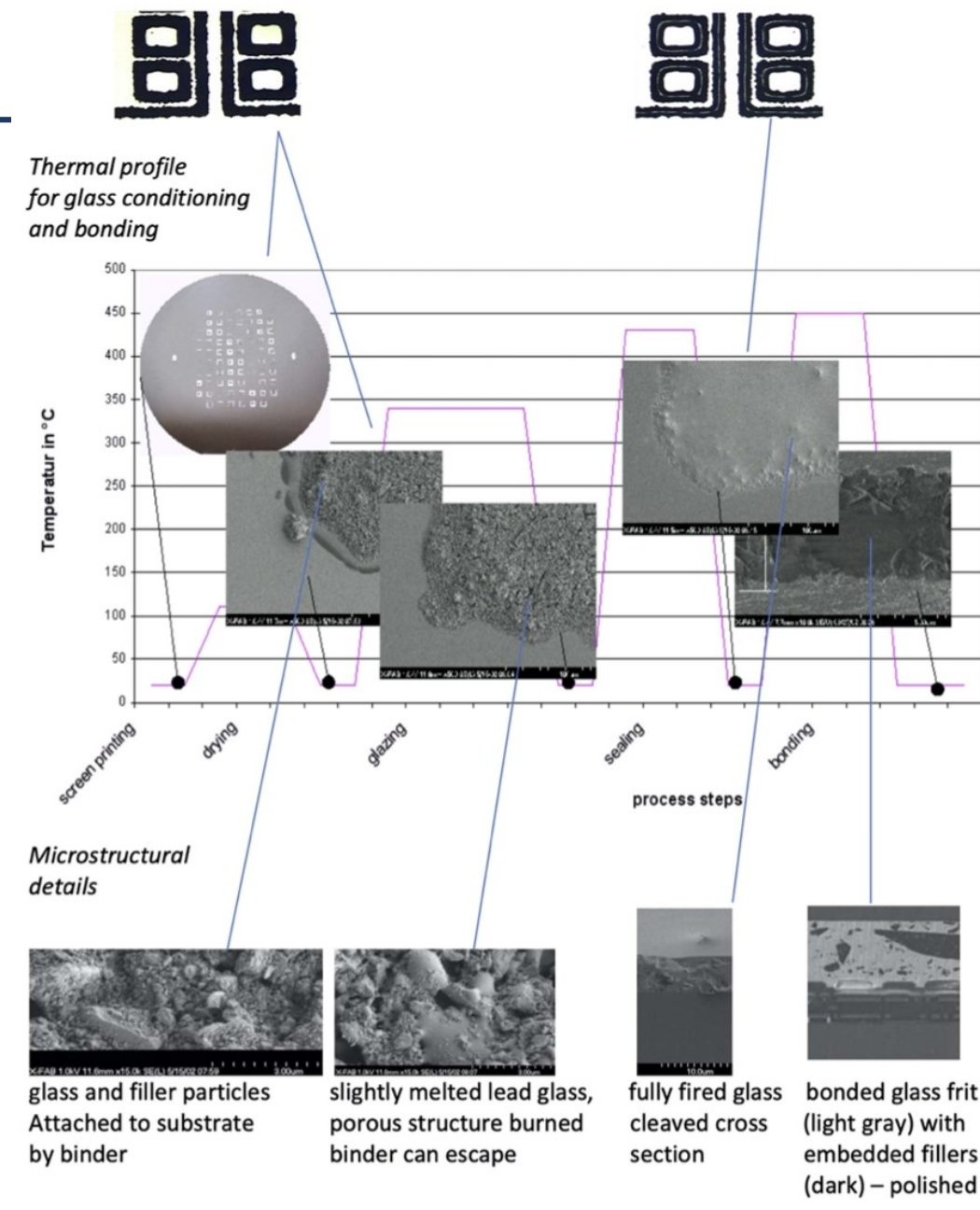
New requirements Chemical and thermal properties of glass frit materials are important for overall process integration  
Maximum process temperatures after glass frit bonding  
Cleaning processes



# Glass Frit Bonding a short Introduction



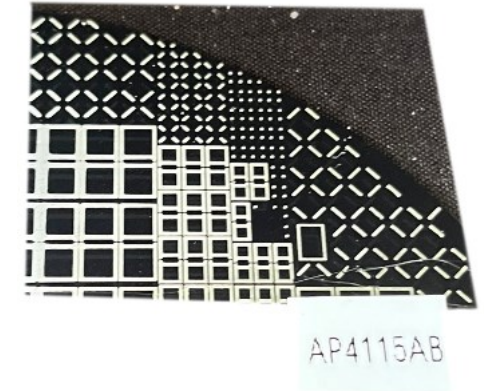
Glass Frit as bonding and sealing material



## Glass Frit Bonding

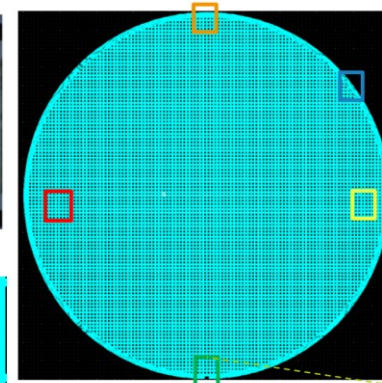
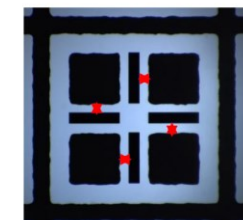
Development of Glass Frit Bonding processes based on lead free materials

Screen Printing – Firing – Bonding – Reliability  
chemical and electrical properties to be investigated  
thermo-mechanical properties important - wafer bow

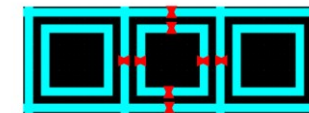


Conflicting requirements for screen printing

Small chips – small bond frames, can lead to high amount of paste covered areas - problems in release of the screen – different optimizations (screen and process) are necessary



Optimal bonding process – time, peak temperature, wafer bow, hermeticity / bonding strength

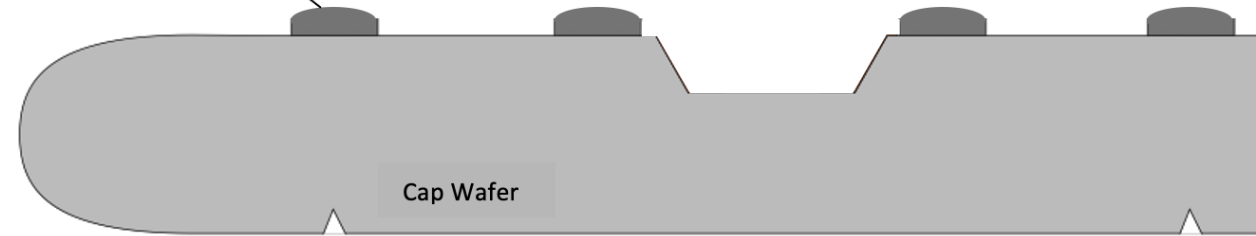


In Wafer Process special configurations are required, such as:

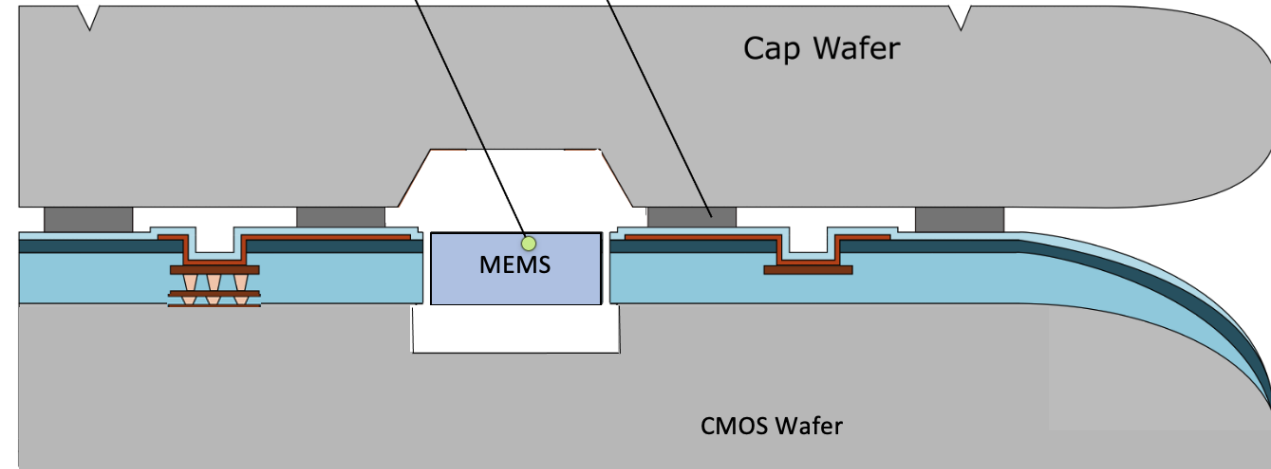
- chip and wafer edge sealing
- small edge exclusion zone
- thermal and chemical glass frit stability

... mostly related to wafer bonding.

a) cap wafer prepared for bonding: **glass frit**  
– screen printed and thermally conditioned



b) Bonded wafer stack **glass frit** as bonding and sealing agent of released **MEMS**



## Conductive Glass Frit Bonding

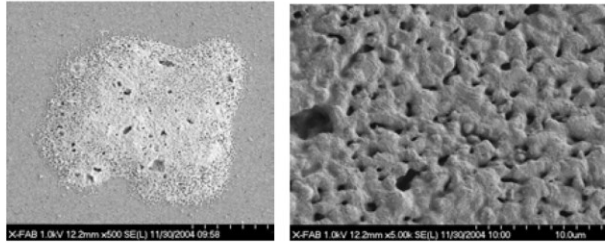


Figure 1: SEM images silver filled conductive glass frit

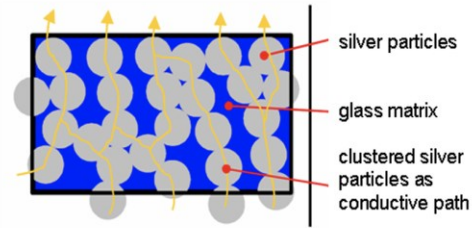
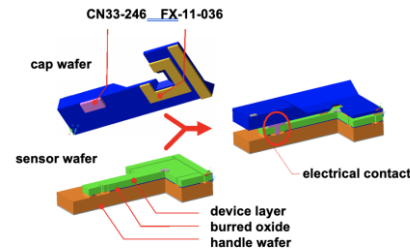
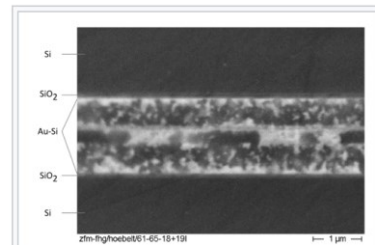


Figure 2: Principle of forming conductive paths in the frit



## Eutectic Bonding

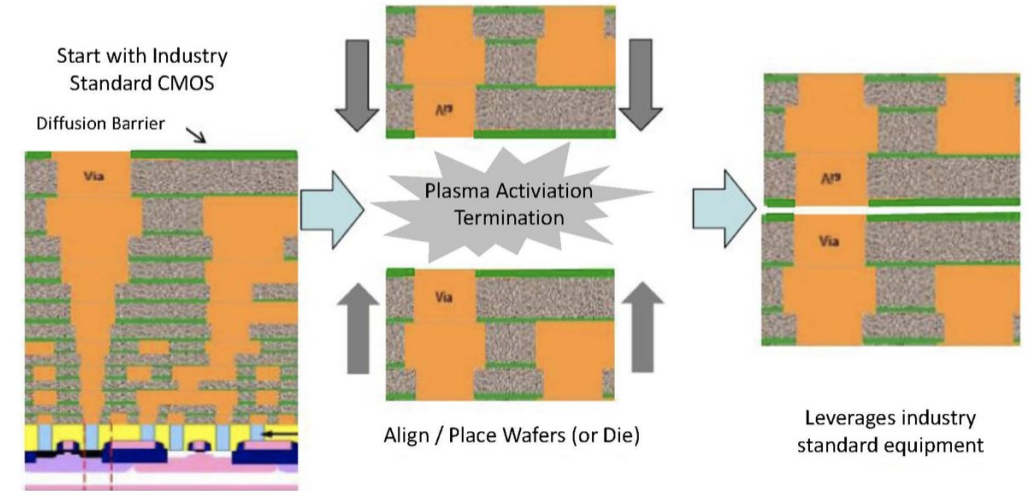
Lin, Y.-C.; Baum M.; Haubold, M.; Fromel J.; Wiemer, M.; Gessner T.; Esashi, M. (2009). "Development and evaluation of AuSi eutectic wafer bonding". *Solid-State Sensors, Actuators and Microsystems Conference, 2009. TRANSDUCERS 2009. International*. pp. 244–247. doi:10.1109/SENSOR.2009.5285519



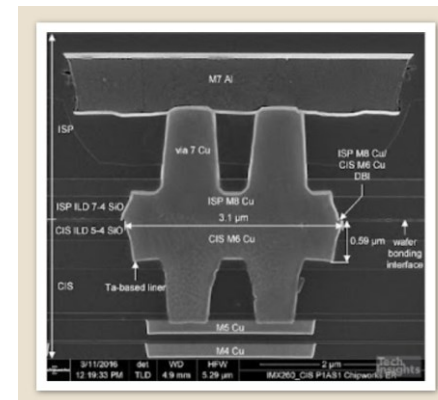
Cross-section SEM image of the bonding interface between Si and Au with 80.3 Si atom percentage.<sup>[1]</sup>

## Hybride Wafer Bonding

Fraunhofer ENAS



Ziptronix Cu-Cu / Oxide "hybrid bonding" Process Flow  
(Source: Permanent Wafer Bonding, Yole Développement, May 2014)

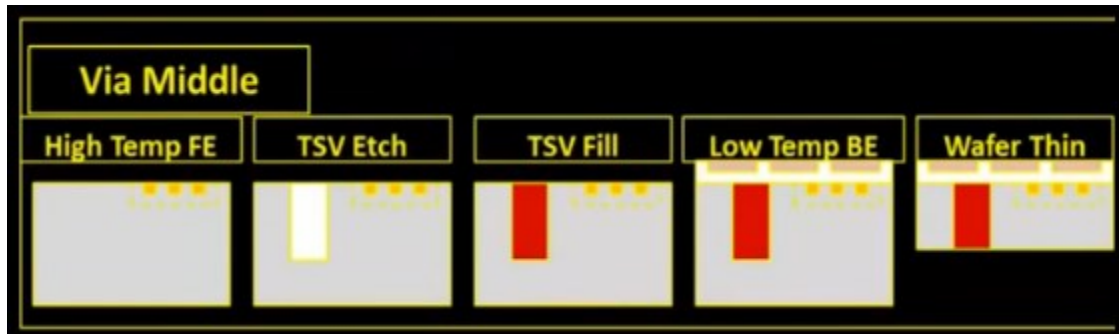


<http://image-sensors-world.blogspot.com/2020/10/hybrid-bonding-review.html>



**Via First:** before device fabrication

- Difficult process integration
- Interactions with CMOS parameters



**Via Middle:** before metal line fabrication

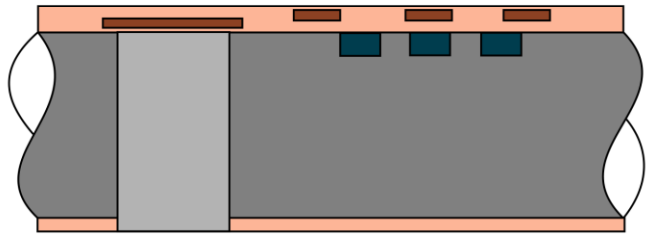
- Difficult process integration
- Interactions with CMOS parameters



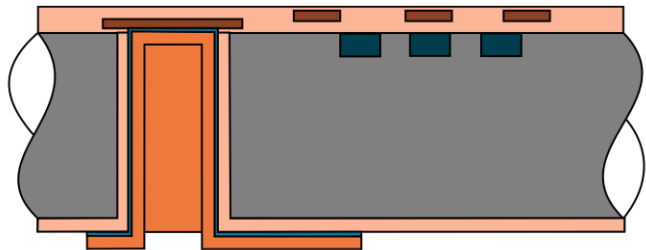
**Via Last:** after metal line fabrication

- Independent from CMOS process
- Independent process module
- Universally applicable

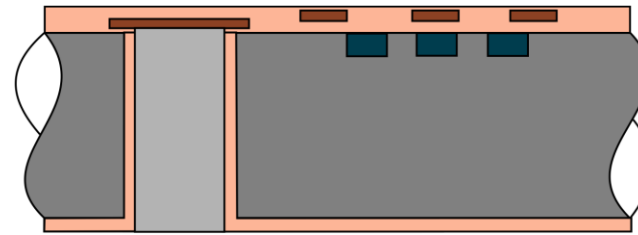
Wafer abdünnen & Ätzen  
der TSVs



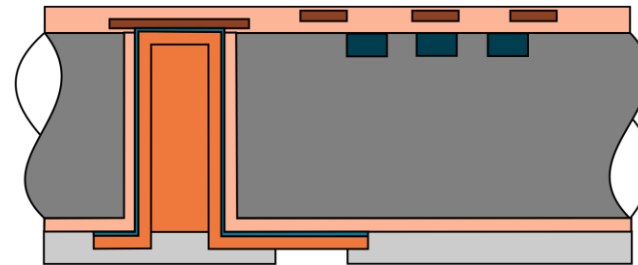
Galvanisches Cu &  
Entfernen B/S



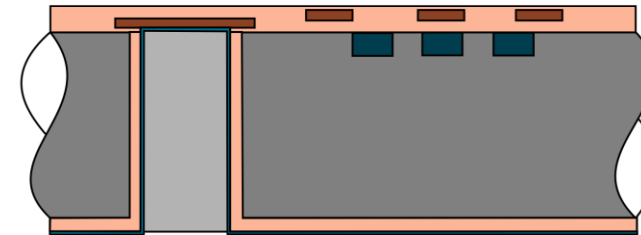
Abscheidung Isolation &  
Öffnen des Metallkontakts



Passivierung der TSVs



Abscheidung Barrier- und  
Saat-Schicht (B/S)



Last process step of TSV is copper metallization,  
but this not solderable

Under Bump Metallization (UBM) is required...

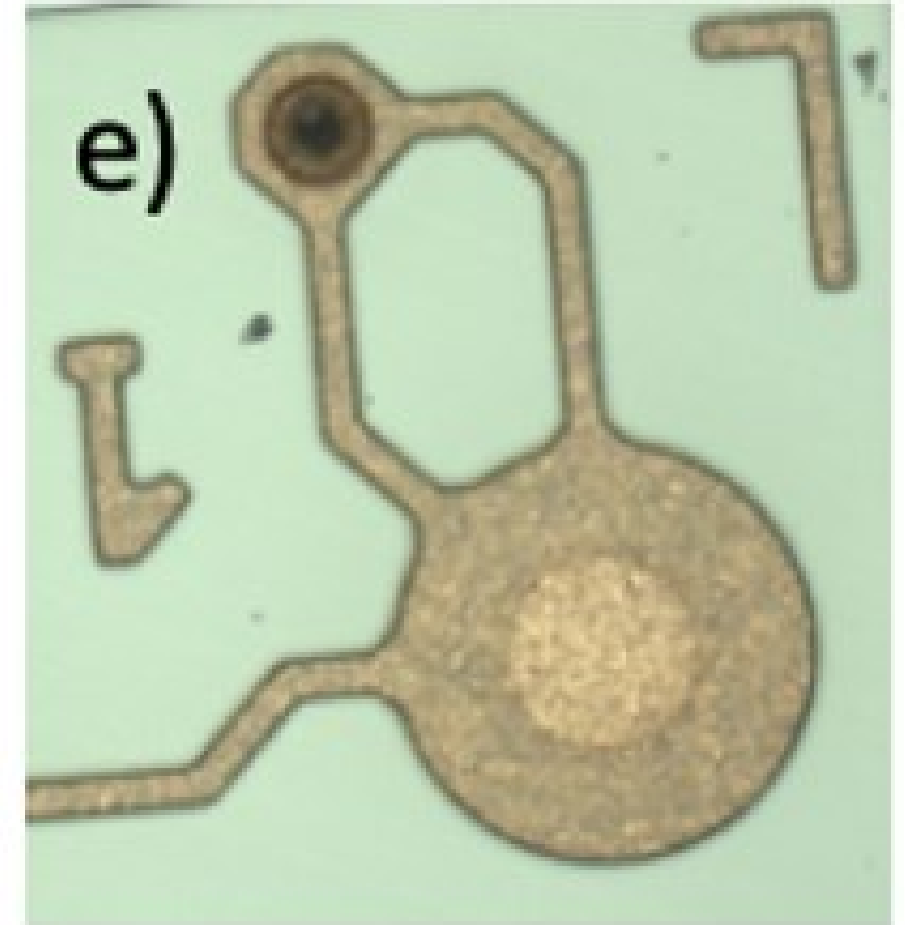
Nickel and Gold

E-less plated or sputtered (Lift off)

... and Solder Stop Layer (SolStop)

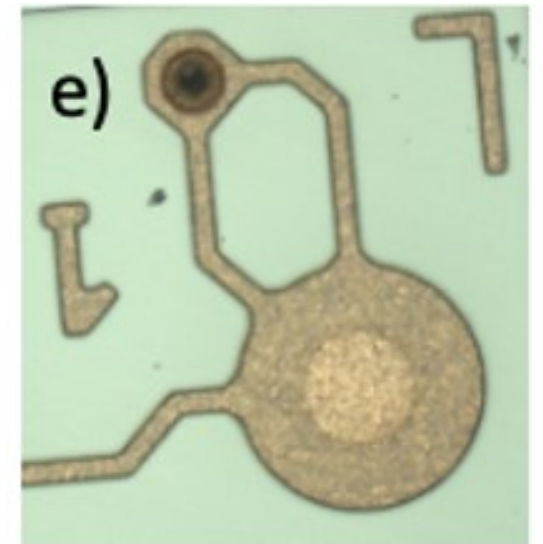
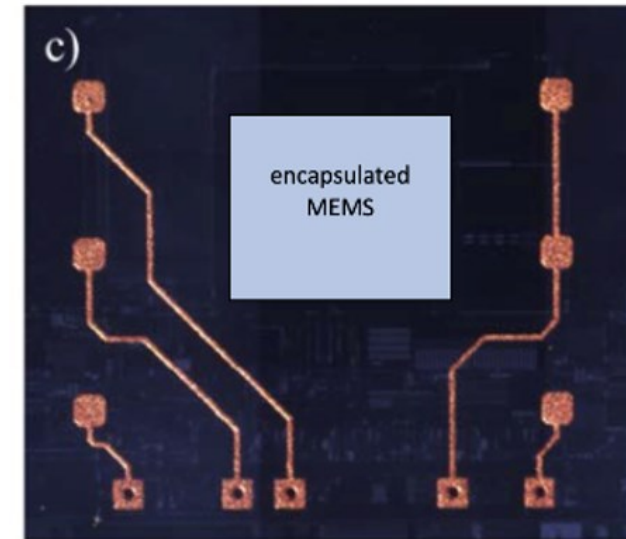
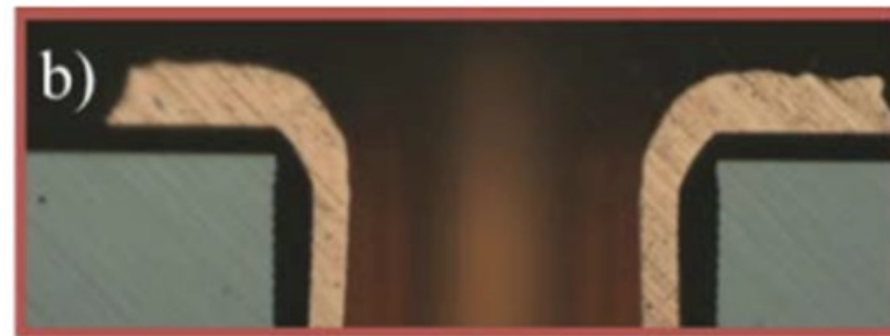
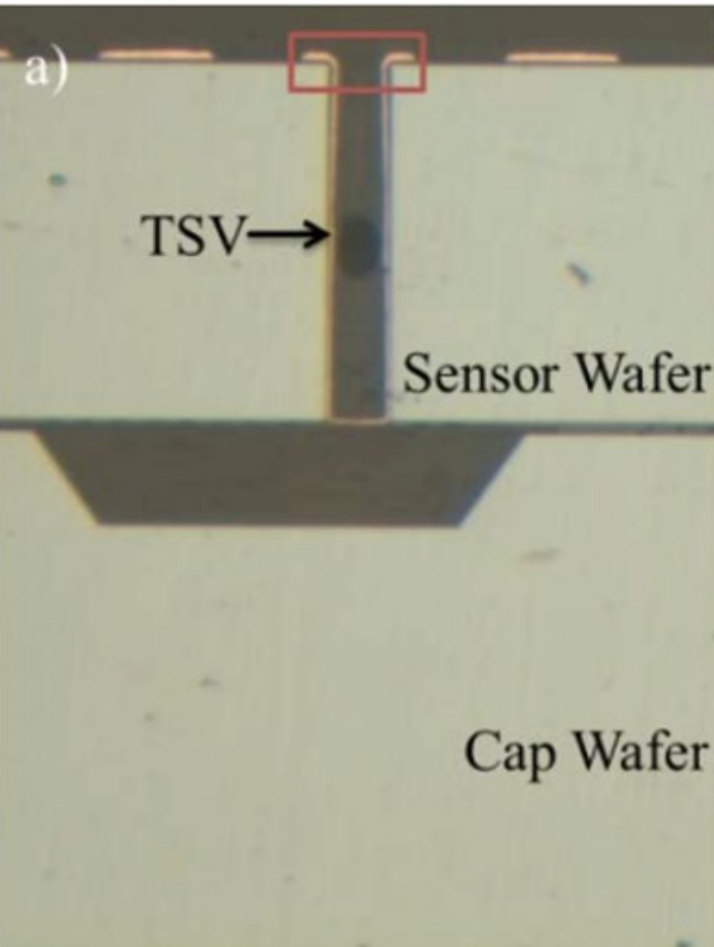
Polymers

Oxide/Nitride...

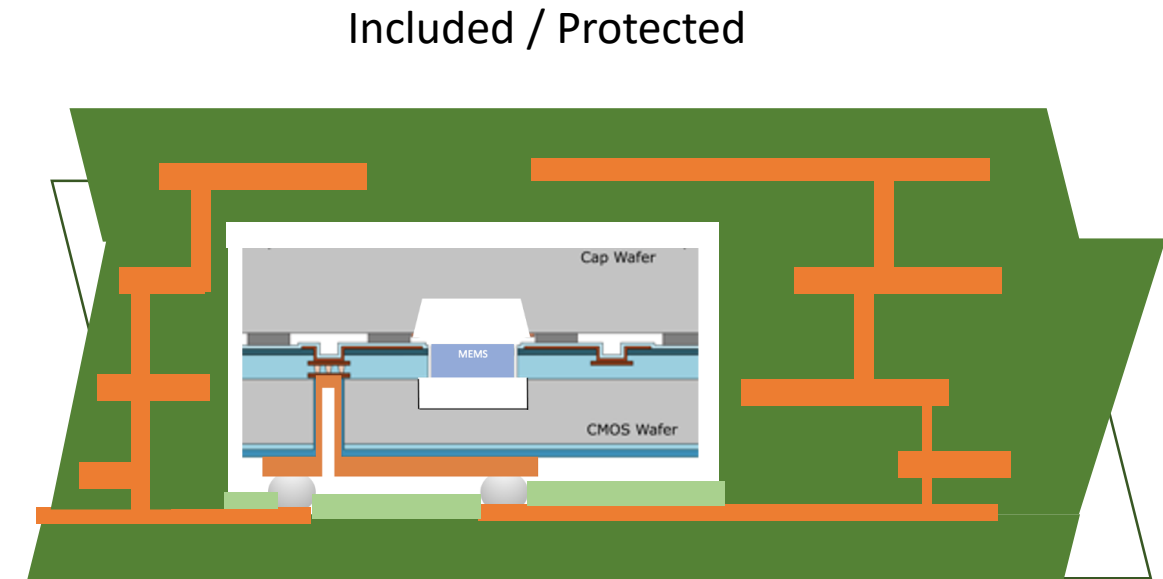
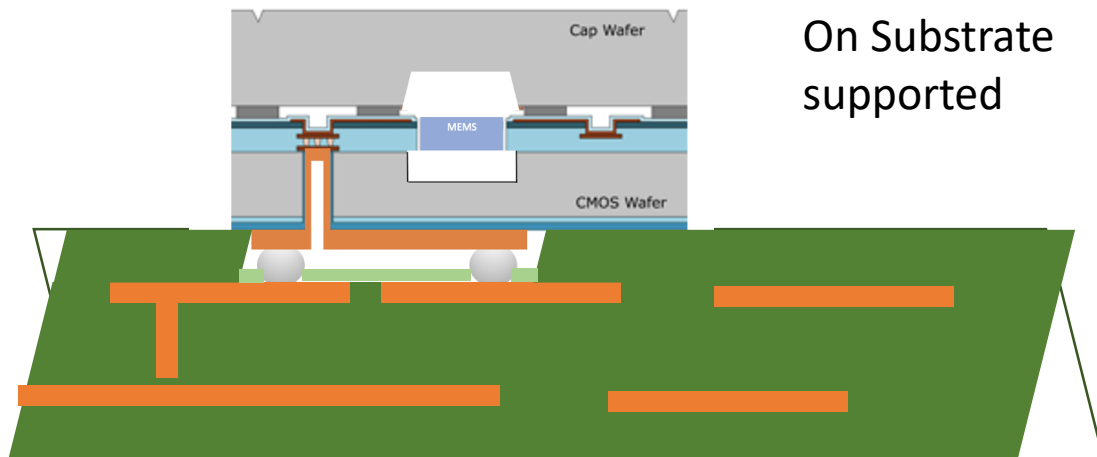
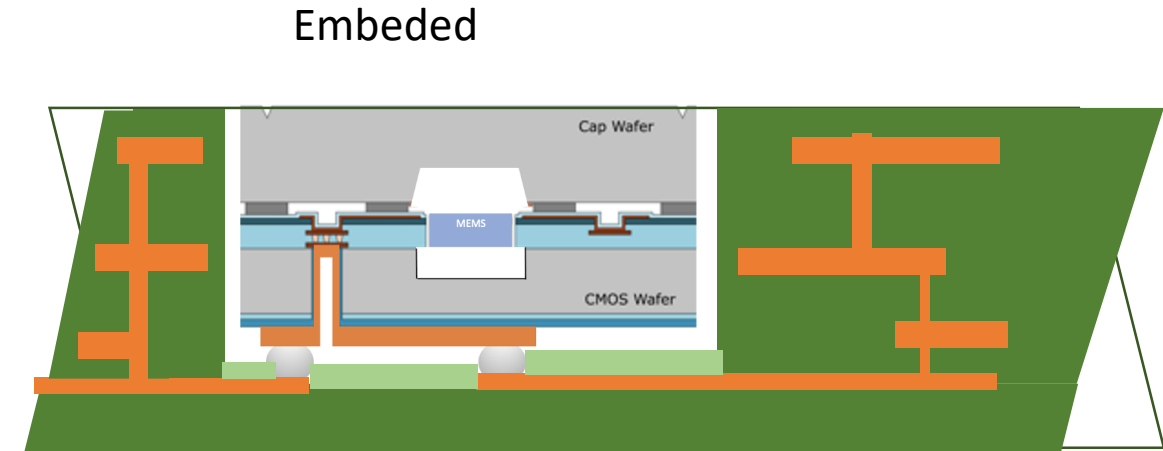
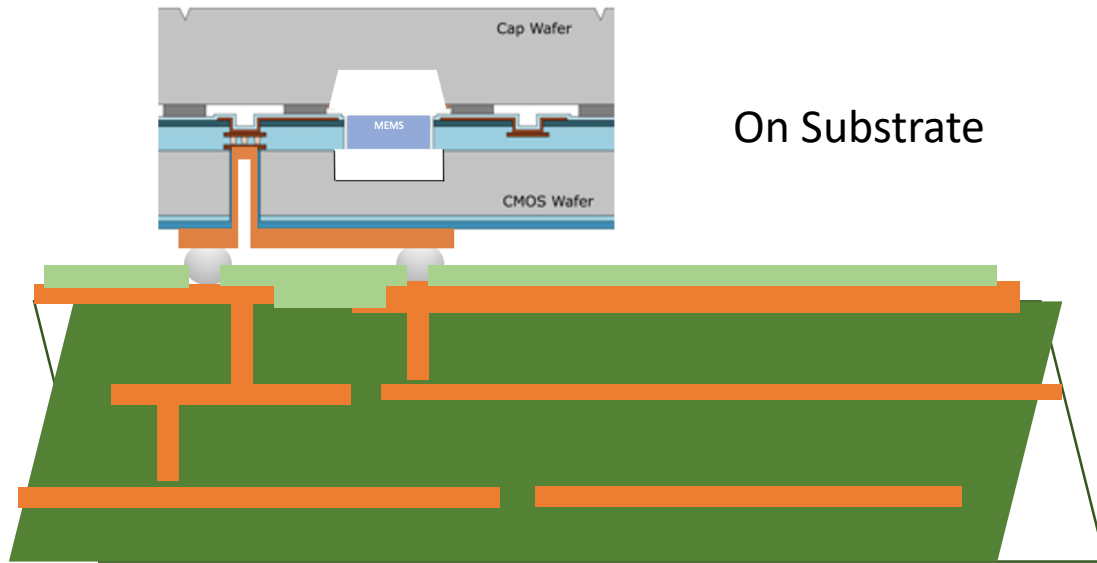


Example e-less Ni/Au at Polymer Passivation

# An example of a System on Chip Chip Scale Package Solutions







## Wafer process

- Overall **technology integration** (e.g., thermal & chemical stability of glass frit bonding during TSV process)
- Preparation of solder process (solder balls – size, material and process; just solderable pads?)
- **Temperature limitation** ( $T > 250^{\circ}\text{C}$  has influence on Cu grain growth)
- **Passivation** material (hard or soft, hydrophobic)
- **Dicing** of bonded wafer stack with hidden CMOS
- Supply chain (longer wafer process, but no assembly process)
- Follow up of commodity products (smaller CSP – out of standardization)
- **Shipment forms** (e.g., on trays, tape on reel)

## Board or ceramic mounting

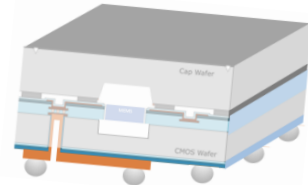
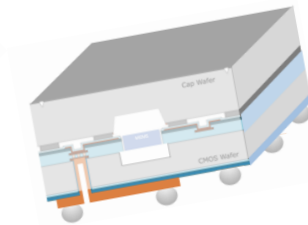
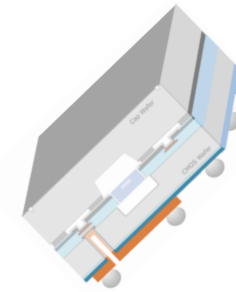
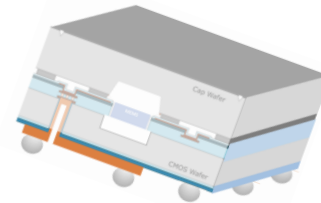
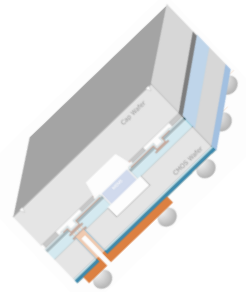
- **Total temperature budget** to be considered (soldering temperature, 5x reflow, low temp. solder required?)
- Does board mounting provide some **protection** (embedded, included, underfill, glob top?)
- **Thermal mechanical stress** (operating temperature, thermal cycles and shocks)
- **Co-design of boards and chips** (bridging critical dimensions)
- **Reliability**
- Cost structures – no assembly, but higher wafer and board costs

*Chip scale packaged, system on chip solutions are becoming reality.* They are providing extreme high integration densities - in themselves, but also for ceramic or BCB solutions (smallest possible from factor).

For such complex and highly integrated systems on chip, realized in wafer processes and without any single die assembly, different process blocks

- (glass frit) wafer bonding
- TSV
- RDL, UBM, SolStop, Solder

... need to be combined and adapted to each other (process integration).



There are quite some challenges in number, but rather work to be done until all details are fitting together.

*For sure, the chances of such solutions are dominating the challenges.*

Roy Knechtel thanks the Carl-Zeiss-Foundation for the funding his professorship.



*Thank you for your Attention!*

I'm open for your questions.

